

AUG 18 2005

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: R. Nagamine et al.

Serial No.: 10/026,532

Group Art Unit: 2133

Filed: December 27, 2001

Examiner: Cynthia H. Britt

For: TEST CIRCUIT FOR LOGICAL INTEGRATED CIRCUIT AND METHOD FOR
TESTING SAME

Honorable Commissioner of Patents
Alexandria, VA 22313-1450

RECORD OF PERSONAL INTERVIEW
AND AMENDMENT UNDER 37 C.F.R. §1.116

Sir:

In response to the Office Action dated May 18, 2005, please amend the above-
identified application as follows: